AMENDMENTS TO THE CLAIMS

In the claims:

- 1. (Currently amended) A semiconductor structure comprising: a substrate, a Sn_xGe_{1-x} Sn_zGe_{1-z} layer formed over the substrate, and an essentially single-phase Ge-Sn-Si $Ge_{1-x-y}Si_xSn_y$ layer formed over the Sn_xGe_{1-x} Sn_zGe_{1-z} layer.
- 2. (Original) The semiconductor structure of claim 1 wherein the substrate comprises silicon.
- 3. (Original) A method for synthesizing a compound having the molecular formula $H_3Si\text{-}GeH_3$, the method comprising combining $H_3SiO_3SCF_3$ with KGeH₃ under conditions whereby $H_3Si\text{-}GeH_3$ is obtained.
- 4. (New) The structure of claim 1, wherein z is about 0.01 to about 0.05.
- 5. (New) The structure of claim 1, wherein x is about 0.01 to about 0.25; and y is about 0.01 to about 0.11.
- 6. (New) The structure of claim 1, wherein x is about 0.01 to about 0.25; y is about 0.01 to about 0.11; z is about 0.01 to about 0.05; and the substrate comprises silicon.
- 7. (New) The structure of claim 1, wherein the $Ge_{1-x-y}Si_xSn_y$ layer is strained.
- 8. (New) The structure of claim 1, wherein the $Ge_{1-x-y}Si_xSn_y$ layer is relaxed.

9. (New) A method to prepare the semiconductor structure according to claim 1, comprising the steps of,

providing a substrate;

depositing a Sn_zGe_{1-z} layer over the substrate; and depositing a $Ge_{1-x-y}Si_xSn_y$ layer over the Sn_zGe_{1-z} layer.

- 10. (New) The method of claim 9, wherein the $Ge_{1-x-y}Si_xSn_y$ layer is deposited by precursor chemical vapor deposition, wherein the precursor chemical vapor comprises SnD_4 and H_3SiGeH_3 .
- 11. (New) The method of claim 9, wherein the $\mathrm{Sn_zGe_{1-z}}$ layer is deposited by precursor chemical vapor deposition, wherein the precursor chemical vapor comprises $\mathrm{SnD_4}$ and $\mathrm{Ge_2H_6}$.
- 12. (New) The method of claim 9, wherein the substrate comprises silicon.
- 13. (New) The method of claim 9, further comprising the step of annealing the Sn_zGe_{1-z} layer prior to depositing the $Ge_{1-x-y}Si_xSn_y$ layer.
- 14. (New) The method of claim 9, wherein z is about 0.01 to about 0.05.
- 15. (New) The method of claim 9, wherein x is about 0.01 to about 0.25; and y is about 0.01 to about 0.11.
- 16. (New) The method of claim 9, wherein x is about 0.01 to about 0.25; y is about 0.01 to about 0.11; z is about 0.01 to about 0.05; and the substrate comprises silicon.

- 17. (New) The method of claim 9, wherein the $Ge_{1-x-y}Si_xSn_y$ layer is deposited at a temperature of about 310°C to about 375°C.
- 18. (New) The method of claim 3, wherein the $H_3SiO_3SCF_3$ and $KGeH_3$ are combined at about -60°C.
- 19. (New) An alloy of the formula, $Ge_{1-x-y}Si_xSn_y$, wherein x is about 0.01 to about 0.25 and y is about 0.01 to about 0.11.
- 20. (New) The alloy of Claim 19, wherein x is about 0.13 to about 0.20.
- 21. (New) The alloy of Claim 20, wherein y is about 0.07 to about 0.11.
- 22. (New) The alloy of Claim 20, wherein y is about 0.01 to about 0.06.
- 23. (New) A semiconductor structure comprising: a substrate, a Sn_zGe_{1-z} layer formed over the substrate, and a layer of the alloy of Claim 19 formed over the Sn_zGe_{1-z} layer.
- 24. (New) The semiconductor structure of claim 23 wherein the substrate comprises silicon.
- 25. (New) The semiconductor structure of Claim 1 wherein the Sn_zGe_{1-z} and $Ge_{1-x-y}Si_xSn_y$ layers are lattice-matched.
- 26. (New) The semiconductor structure of Claim 23 wherein the Sn_zGe_{1-z} and $Ge_{1-x-y}Si_xSn_y$ layers are lattice-matched.

27. (New) A structure comprising: a Sn_zGe_{1-z} layer and a layer of the alloy of Claim 19 formed over the Sn_zGe_{1-z} layer.